

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/082,794	<b>Applicant(s)/Patent under Reexamination</b> BAU ET AL.
	<b>Examiner</b> J. Derek Rutten	<b>Art Unit</b> 2192

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner